30V, 40A, 11.3mΩ N-channel Power Trench MOSFET

JMTQ3400D

Features

- $\bullet \;\;$ Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- Pb-free plating

Applications

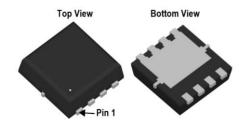
- Load Switch
- PWM Application
- Power Management

Product Summary

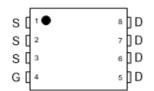
Parameters	Value	Unit
V_{DSS}	30	٧
$V_{GS(th)_Typ}$	1.0	V
$I_{D}(@V_{GS}=10V)$	40	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	10.6	mΩ
$R_{DS(ON)_Typ}(@V_{GS}=4.5V$	11.3	mΩ



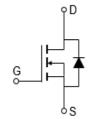








Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTQ3400D	Q3400D	1	Tape&Reel	PDFN3x3-8L	5000	50000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		30	V
V_{GS}	Gate-to-Source Voltage		±12	V
I_	Continuous Drain Current	$T_C = 25^{\circ}C$	40	^
I _D		$T_C = 100$ °C	25	- A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		31	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	40	W
		$T_C = 100$ °C	16	\ \v\
T_{J}, T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol Parameter		Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	52	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.1	C/VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

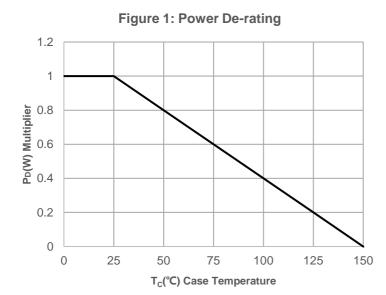
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	nracteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 12V$	-	-	±100	nA
On Cha	racteristics			•		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.7	1.0	1.3	V
D	Ctatic Ducie Course ON Decistor of (4)	$V_{GS} = 10V, I_D = 4.2A$	-	10.6	13.8	mΩ
$R_{DS(ON)}$	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 4.5V, I_D = 4A$	-	11.3	14.7	mΩ
Dynami	ic Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	1.0	-	Ω
C _{iss}	Input Capacitance	24 254 454	1095	1533	2069	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 15V,$ $f = 1MHz$	84	118	160	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	67	94	126	pF
Qg	Total Gate Charge		11	16	21	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 15V, I_{D} = 6A$	-	3.3	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	3.5	-	nC
	ng Characteristics	T			ı	ı
t _{d(on)}	Turn-On DelayTime	_	-	10	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 15V$	-	23	-	ns
$t_{\text{d(off)}}$	Turn-Off DelayTime	$I_D = 6A, R_{GEN} = 3\Omega$	-	33	-	ns
t _f	Turn-Off Fall Time		-	6.8	-	ns
Body D	iode Characteristics				·	
I _S	Maximum Continuous Body Diode Forward Current		-	-	40	Α
I_{SM}	Maximum Pulsed Body Diode Forward Cur	rent	-	-	159	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 4.5A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	1 - 4 2 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	9	12	17	ns
Qrr	Body Diode Reverse Recovery Charge	$I_F = 4.2A$, di/dt = 100A/us	-	5.2	-	nC

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- $2.\;E_{AS}\;condition:\;Starting\;T_{J}=25C,\;V_{DD}=15V,\;V_{GS}=10V,\;R_{G}=25ohm,\;L=0.5mH,\;I_{AS}=11.2A,\;V_{DD}=0V\;during\;time\;in\;avalanche.$
- 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 0.5%.



Typical Performance Characteristics



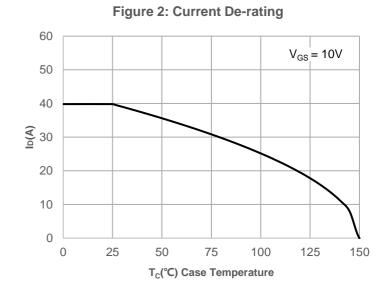
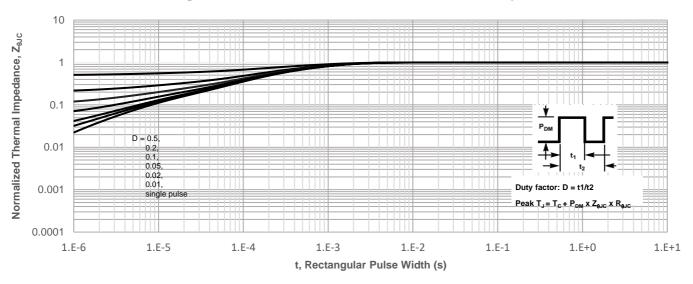


Figure 3: Normalized Maximum Transient Thermal Impedance



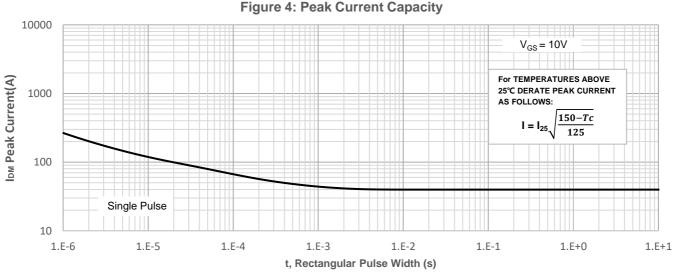


Figure 4: Peak Current Capacity



Typical Performance Characteristics

Figure 5: Output Characteristics

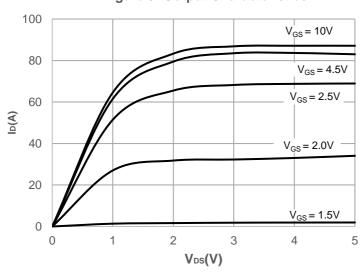


Figure 6: Typical Transfer Characteristics

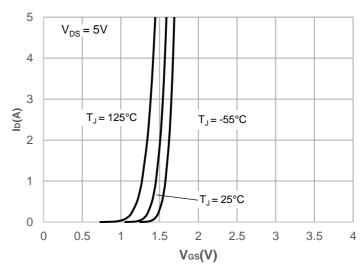


Figure 7: On-resistance vs. Drain Current

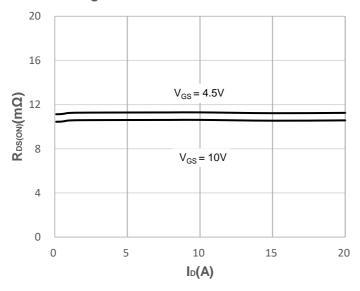


Figure 8: Body Diode Characteristics

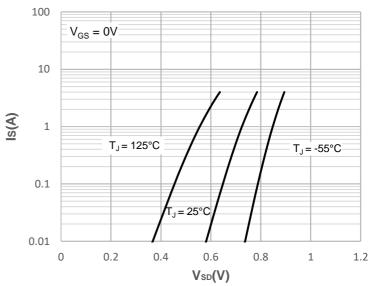


Figure 9: Gate Charge Characteristics

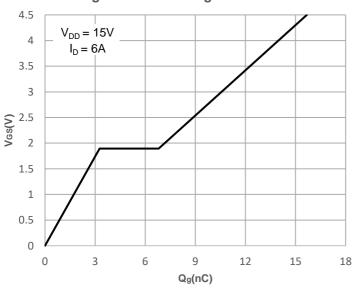
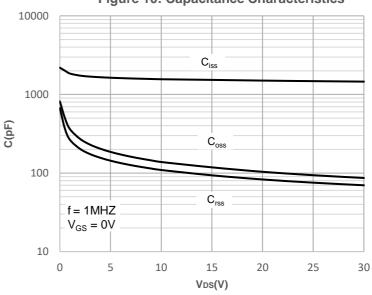


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

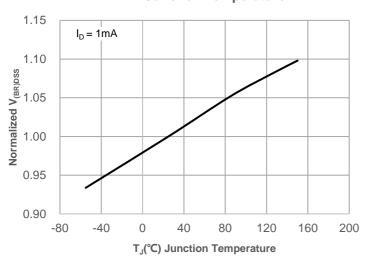


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

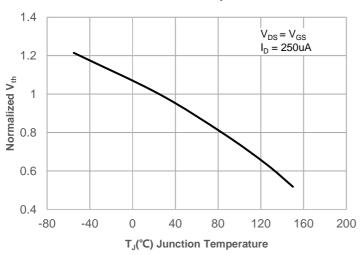


Figure 15: Maximum Safe Operating Area

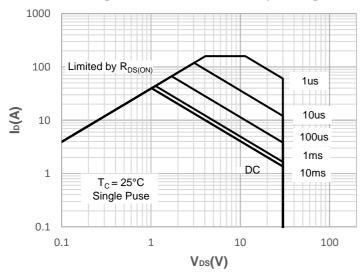
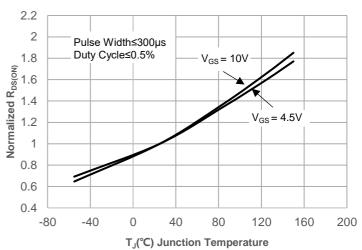
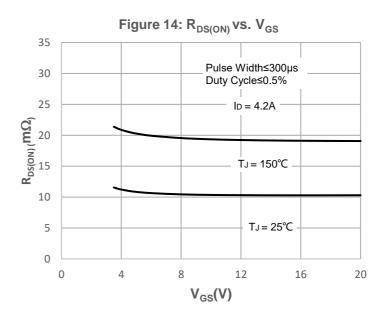


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

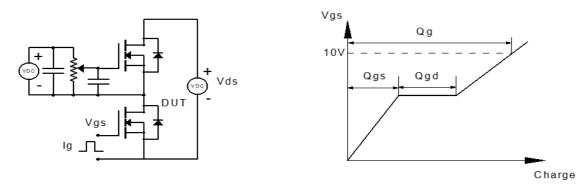


Figure 1: Gate Charge Test Circuit & Waveform

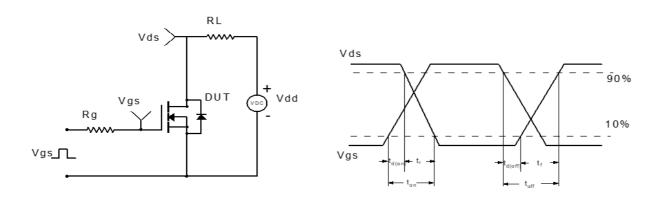


Figure 2: Resistive Switching Test Circuit & Waveform

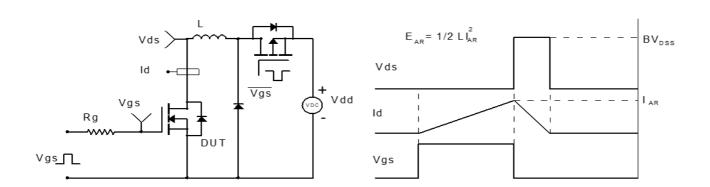


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

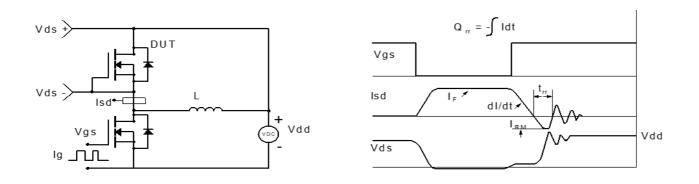
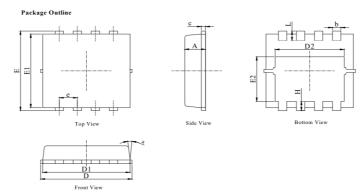


Figure 4: Diode Recovery Test Circuit & Waveform



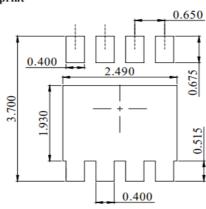
Package Mechanical Data(PDFN3X3-8L)



- DIMENSIONING AND TOLERANCING PER ASME
- ALL DIMNESIONS IN MILLIMETER (ANNGLE IN DEGREE).
- DIMENSIONS DI AND EI DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM.	MILLIMETER				
DIM.	MIN.	NOM.	MAX.		
A	0.70	0.75	0.80		
ь	0.25	0.30	0.35		
С	0.10	0.20	0.25		
D	3.00	3.15	3.25		
D1	2.95	3.05	3.15		
D2	2.39	2.49	2.59		
E	3.20	3.30	3.40		
E1	2.95	3.05	3.15		
E2	1.70	1.80	1.90		
e	0.65 BSC				
Н	0.30	0.40	0.50		
L	0.25	0.40	0.50		
a			15°		

Recommended Soldering Footprint



DIMENSIONS:MILLIMETERS

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